



4/5

Best Available Copy

Thin-Layer Micrometrology
and Thin-Layer Macrometrology
combined

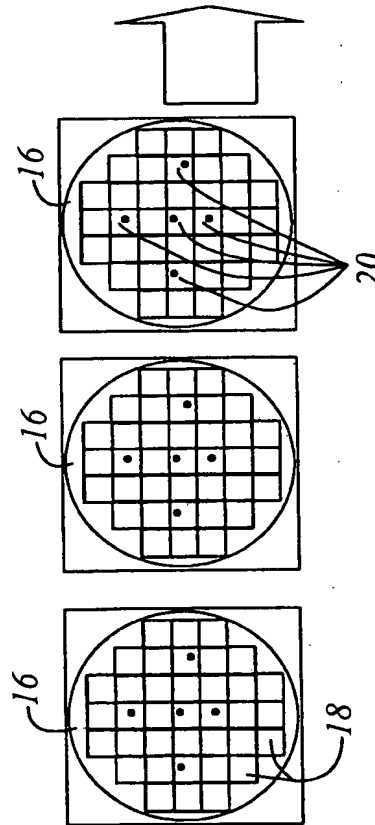
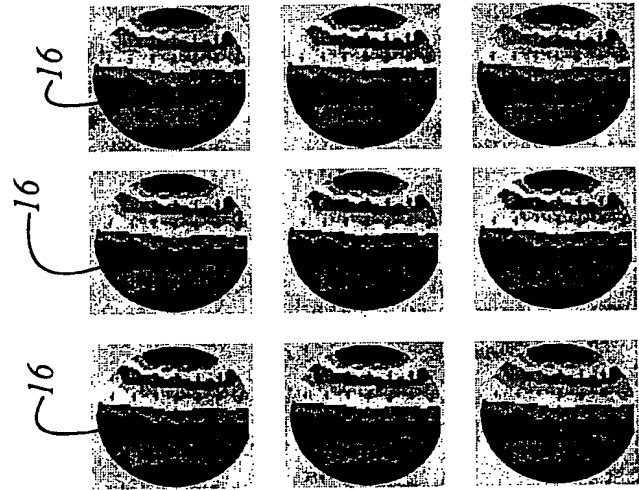
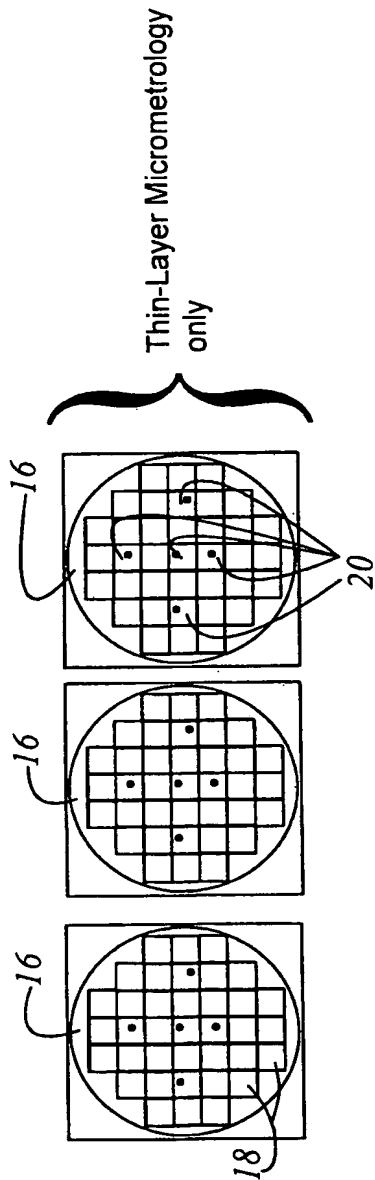


Fig. 5